Remarks: Das long as sample size is fixed, cannot decrease both dand B at once by changing writical region.

by collecting more data, can reduce a & B.

2) The selection of the threshold (or in general, critical region) is based on application.

Ex: Blood Test for HIV.

Ho = You don't have HN. H, = you have HIV.

let X be thevalve of HIV-Level. assume higher value of X, more likely to have HIV.

how to decide threshold t for acceptance region × = t?

Want to make & small; caremore about & type I error rate (false negative).

Ex: Consider A RS $X_1,...,X_n$ from a normal population with $\sigma^2=1$. Want to trest hypotheses: $H_0: \quad \mathcal{U}=\mathcal{U}_0 \quad \text{vs. } H_1: \quad \mathcal{U}=\mathcal{U}_1, \quad \text{where} \quad \mathcal{U}_1>\mathcal{U}_0$

find value K so that X>K provides a critical region for which x=0.05.

(60ess: K= M. + Zoos) Note ~= P(M=Mo, X>K)

under H_o , $\overline{X} \sim N(\mu_o, \frac{1}{n})$ so $\frac{\overline{X} - \mu_o}{\frac{1}{\sqrt{n}}} \sim N(0, 1)$

So
$$\mathbb{P}\left(\frac{x-x_{0}}{\sqrt{x}} > \frac{k-x_{0}}{\sqrt{x}}\right) = 0.5$$

$$\Rightarrow K = M_{0} + Z_{0.05} \frac{1}{\sqrt{x}}$$

$$= M_{0} + 1.65 \frac{1}{\sqrt{x}}$$

w/ a = 0.00

Q: to test Ho: M=10 Vs Hi: N=11, find minimal sample size needed in order to have \$60.06

$$P = P(\text{accept Hoi Hois false})$$

$$\text{Under Ho, this is } P(X < K, M = 11) = P(\frac{X - 1}{\frac{1}{100}} < \frac{K - 11}{\frac{1}{100}})$$

$$\text{Nont this } = -2$$

$$-10/\sqrt{2} - 11$$

$$10 + 1.65 \frac{1}{100} - 11$$

$$= \mathbb{P}\left(\frac{x-11}{x} < \frac{10+1.65\sqrt{x}-11}{\sqrt{x}}\right) = 0.06$$

so wen+
$$1.65 - \sqrt{n} \le -Z_{0.06} = -1.56$$
, so wen+ $n > (-1.56 - 1.65)^2$ ≈ 10.3

50 n≥11 is necessary.

Remark: In "Chosical" typ. testing, restrict ourselves to tests for which a is specified to be acceptably low. querally, a < 0.05, but 0.01 and 0.1 are also used. Sometimes don't have ets dist so counst pick x=0.05.

§ 2.4: Neyman-Pearson Lemma:

P(reject Hoi Ho is fulse) Consider fixed a and box for tests that minimize B (or maximize 1-B) where I-B is the power of the test. We would like to find tests that maximize power for particular alternatives.

let f(x;0) be dist. of a pop.

Lonsider testing $H_0: \theta = \theta_0$ and $H_1: \theta = \theta_1$ (simple vs. simple)

would like to find test that his max power at 0=0,.

This is called the "best" or "most powerful" test, and corresponding critical region is called the "most powerful" critical region.

Given a sample X1,..., Xn. to construct such a test, consider likelihood under two hypotheses $L_{\bullet} = \prod_{i=1}^{n} f(x_{i}; \theta_{\bullet}), \qquad L_{\downarrow} = \prod_{i=1}^{n} f(x_{i}; \theta_{i}).$

Reject to when Lo snull and Li big. one way is to book at ratio Lo Rejection/Critical region.

- for the values of sample points that full inside critical region, Lo should be small.

Define critical region to be $\left\{ \vec{\chi} : \frac{L_o(\vec{x})}{L_i(\vec{x})} \leq K \right\}$